

<b>Notice of References Cited</b>	Application/Control No. 10/562,986		Applicant(s)/Patent Under Reexamination HIDAKA ET AL.	
	Examiner John P. Sheehan		Art Unit 1793	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2003/0172995 A1	09-2003	Makita et al.	148/101
*	C	US-6,254,694 B1	07-2001	Hasegawa et al.	148/101
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**NON-PATENT DOCUMENTS**

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